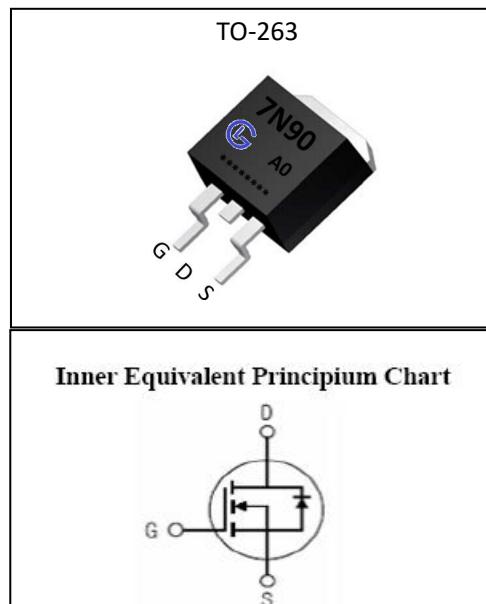


General Description:

GL7N90AO the silicon N-channel Enhanced VDMOSFETS is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency. The package form is TO-263, which accords with the RoHS standard.

V_{DSS}	900	V
I_D	7	A
$P_D (T_c=25^\circ C)$	160	W
$R_{DS(ON)TYP}$	1.4	Ω



Features:

- Fast Switching
- Low Gate Charge and $R_{DS(on)}$
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

Applications:

Power switch circuit of adaptor and charger.

Absolute ($T_c = 25^\circ C$ unless otherwise specified):

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	900	V
I_D	Continuous Drain Current	7.0	A
	Continuous Drain Current $T_c = 100^\circ C$	5.0	A
I_{DM}^{a1}	Pulsed Drain Current	28	A
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}^{a2}	Single Pulse Avalanche Energy	700	mJ
E_{AR}^{a1}	Avalanche Energy ,Repetitive	60	mJ
I_{AR}^{a1}	Avalanche Current	2.4	A
dv/dt^{a3}	Peak Diode Recovery dv/dt	5.0	V/ns
P_D	Power Dissipation	160	W
	Derating Factor above $25^\circ C$	1.28	W/ $^\circ C$
T_J, T_{stg}	Operating Junction and Storage Temperature Range	150, -55 to 150	$^\circ C$
T_L	MaximumTemperature for Soldering	300	$^\circ C$



GL7N90AO

GL Silicon N-Channel Power MOSFET

Electrical Characteristics ($T_c = 25^\circ C$ unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	900	--	--	V
$\Delta BV_{DSS}/\Delta T_J$	Bvdss Temperature Coefficient	$I_D=250\mu A$, Reference $25^\circ C$	--	0.8	--	$V/^\circ C$
I_{DSS}	Drain to Source Leakage Current	$V_{DS} = 900V, V_{GS} = 0V, T_a = 25^\circ C$	--	--	1	μA
		$V_{DS} = 720V, V_{GS} = 0V, T_a = 125^\circ C$	--	--	250	
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS} = +30V$	--	--	10	μA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS} = -30V$	--	--	-10	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10V, I_D=3.0A$	--	1.4	1.8	Ω
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.5	--	4.5	V
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g_{fs}	Forward Transconductance	$V_{DS}=15V, I_D = 3A$	--	8.0	--	S
C_{iss}	Input Capacitance		--	1460	--	pF
C_{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 25V, f = 1.0MHz$	--	130	--	
C_{rss}	Reverse Transfer Capacitance		--	23	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D = 7.0A, V_{DD} = 450V, V_{GS} = 10V, R_G = 9.1\Omega$	--	22	--	ns
tr	Rise Time		--	45	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	33	--	
t_f	Fall Time		--	37	--	
Q_g	Total Gate Charge	$I_D = 7.0A, V_{DD} = 450V, V_{GS} = 10V$	--	37	--	nC
Q_{gs}	Gate to Source Charge		--	8.0	--	
Q_{gd}	Gate to Drain ("Miller")Charge		--	14	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I _S	Continuous Source Current (Body Diode)		--	--	7	A
I _{SM}	Maximum Pulsed Current (Body Diode)		--	--	28	A
V _{SD}	Diode Forward Voltage	I _S =7.0A, V _{GS} =0V	--	--	1.5	V
t _{rr}	Reverse Recovery Time	I _S =7.0A, T _j = 25 °C	--	380	--	ns
Q _{rr}	Reverse Recovery Charge	dI _f /dt=100A/us, V _{GS} =0V	--	1400	--	nC
Pulse width tp≤380μs, δ ≤2%						

Symbol	Parameter	Typ.	Units
R _{θJC}	Junction-to-Case	0.782	°C/W
R _{θJA}	Junction-to-Ambient	62	°C/W

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

^{a2}: L=10.0mH, I_D=11.8A, Start T_j=25 °C

^{a3}: I_{SD} =7A, dI/dt ≤100A/us, V_{DD}≤BV_{DS}, Start T_j=25 °C

Test Circuit and Waveform

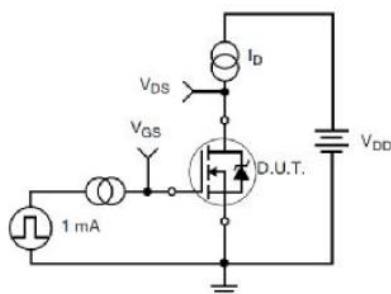


Figure 17. Gate Charge Test Circuit

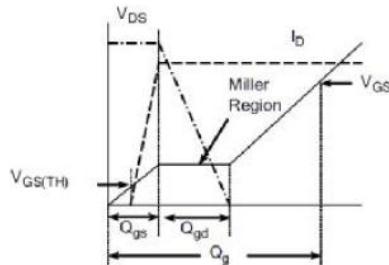


Figure 18. Gate Charge Waveform

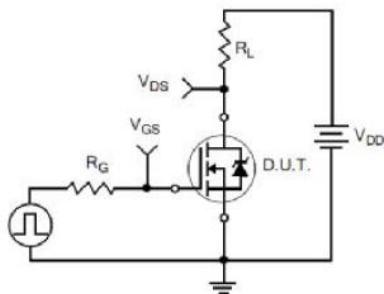


Figure 19. Resistive Switching Test Circuit

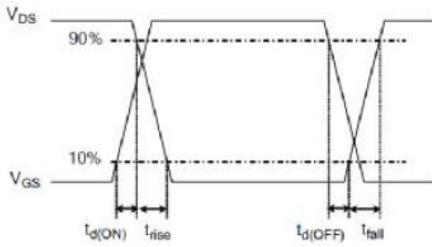


Figure 20. Resistive Switching Waveforms

Characteristics Curve:

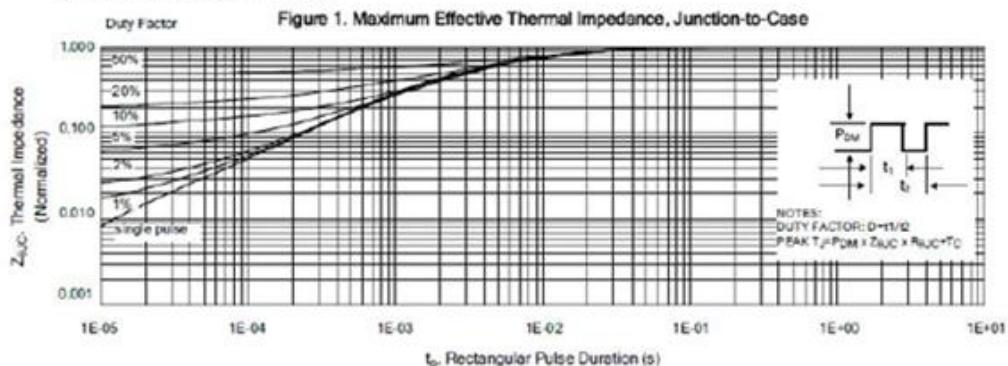


Figure 2. Maximum Power Dissipation vs Case Temperature

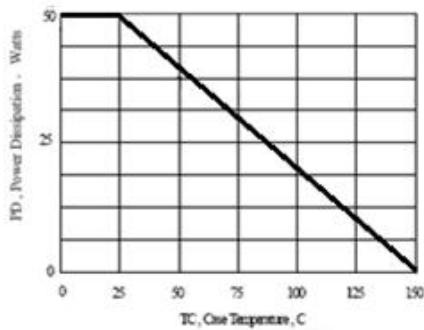


Figure 3. Maximum Continuous Drain Current vs Case Temperature

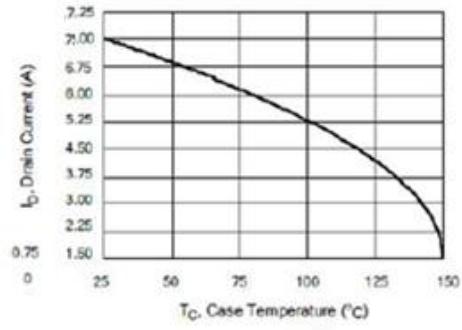


Figure 4. Typical Output Characteristics

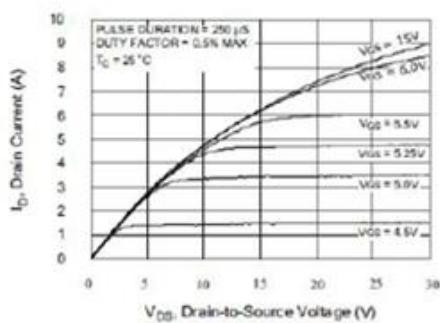


Figure 5. Typical Drain-to-Source ON Resistance vs Gate Voltage and Drain Current

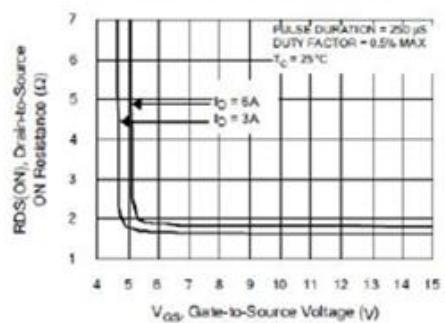


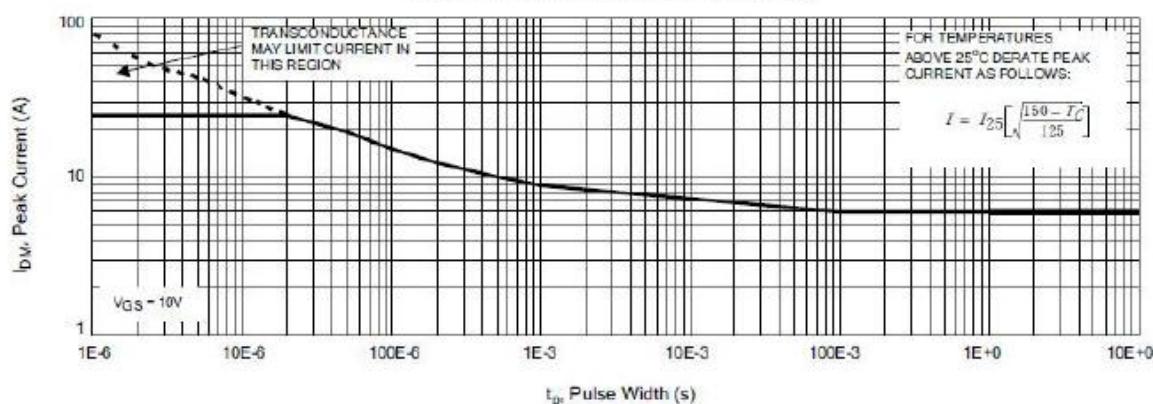
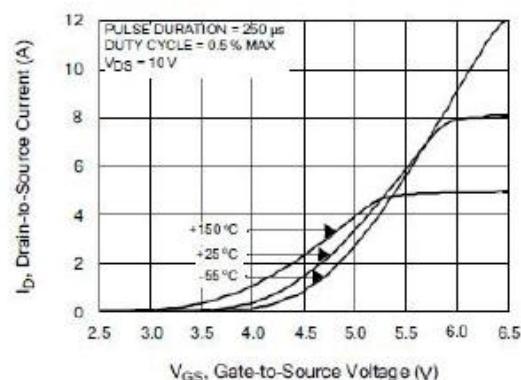
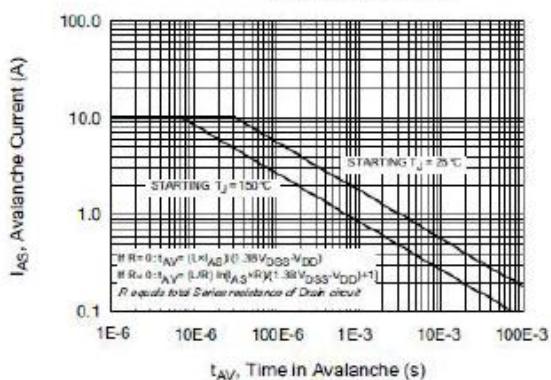
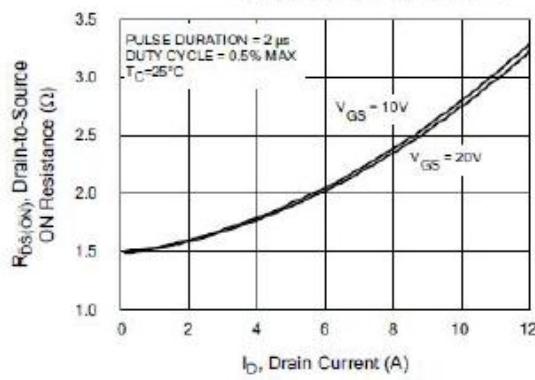
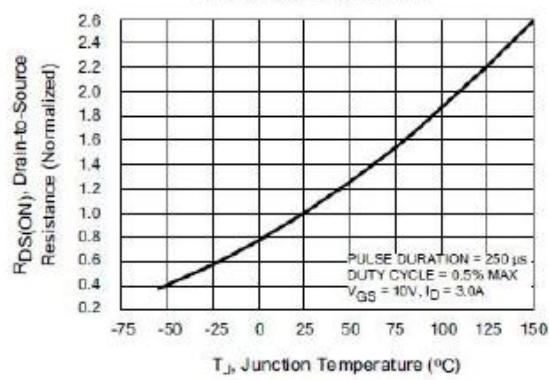
Figure 6. Maximum Peak Current Capability

Figure 7. Typical Transfer Characteristics

Figure 8. Unclamped Inductive Switching Capability

Figure 9. Typical Drain-to-Source ON Resistance vs Drain Current

Figure 10. Typical Drain-to-Source ON Resistance vs Junction Temperature


Figure 11. Typical Breakdown Voltage vs Junction Temperature

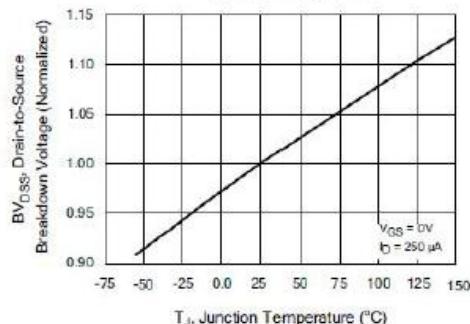


Figure 12. Typical Threshold Voltage vs Junction Temperature

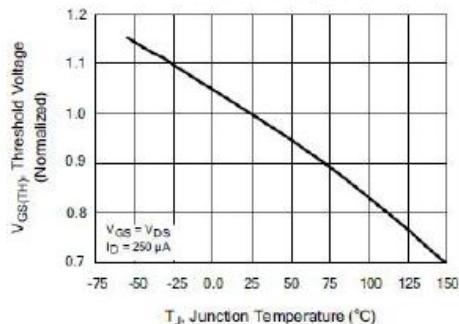


Figure 13. Maximum Forward Bias Safe Operating Area

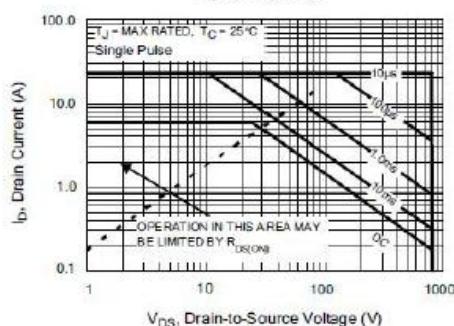


Figure 14. Typical Capacitance vs

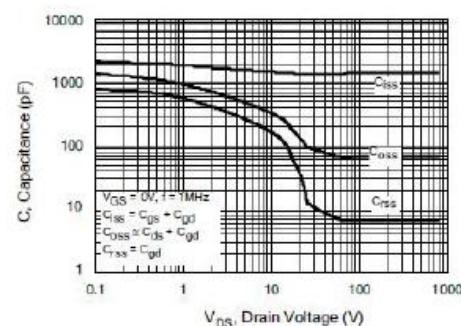


Figure 15. Typical Gate Charge vs Gate-to-Source Voltage

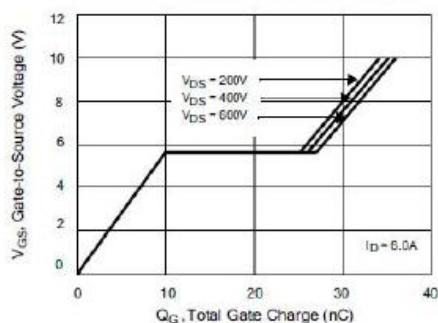


Figure 16. Typical Body Diode Transfer Characteristics

